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501.37892X00/219801044US01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Yoko IKEDA *et al.*
Serial No. : 09/452,149RCE
Filed : 1 December 1999
For : INSPECTING METHOD, INSPECTING SYSTEM, AND
METHOD FOR MANUFACTURING ELECTRONIC DEVICES
Group AU : 2623
Examiner : Samir Anwar Ahmed
Conf. No. : 9942

AMENDMENT

Mail Stop Amendment

Commissioner for Patents

POB 1450

Alexandria, Virginia 22313-1450

06 September 2005

Sir:

In response to the 06 June 2005 Final Office Action in connection with the above-identified application, Applicant respectfully submits the following amendments and remarks.

In accordance with 37 CFR §1.121 in the Final Rule effective 30 July 2003, and as revised in the Final Rule effective 21 October 2004, each section of amendment begins on a new page, and changes are shown by strike-through (or double brackets where appropriate) and underlining to indicate deletions and additions, respectively. A complete listing of all claims ever presented in the application is given with the current status of each claim, and only the text of all pending and withdrawn claims is presented in full, with those pending/withdrawn claims not being amended herein being presented in clean version.